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Meaningful Innovation in Corporate Activities from the Viewpoint of Financial Data

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Yuji Matsuno All Authors

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Abstract:
 A meaningful innovation in corporate activities is not a mere discovery or inventions but a series of corporate activities that create effective economic effects for business activities. Effective economic effects for business activities are increases in sales, operating profit, productivity, current assets, fixed assets, total assets, surplus profits. From the financial data of the listed companies of the Tokyo Stock Exchange (TSE) first and second section between 1956 and 2016 and the listed companies of Japanese Association Of Securities Dealers Automated Quotations (JASDAQ) and Market of the high-growth and emerging stocks (Mothers) between 1987 and 2016, the rate of change of these indices was determined. When the rate of change of these indices of a company were continuously increased, meaningful innovation should have occurred in the company. Next, I collected some case studies on companies that judged that meaningful innovation had occurred, classified them according to indicators that showed an increasing trend, and organized the causes of innovation by type. By doing this, I generalize the causes of innovation obtained from case studies of individual companies and clarify the cause of each type of innovation. In addition, I will clarify the direction of the case study for companies that have not been subject to research.

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